

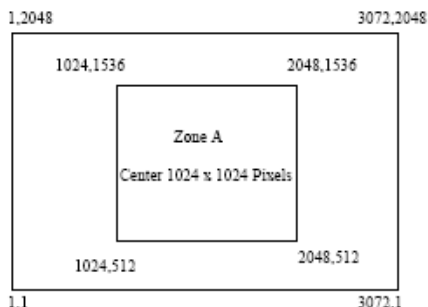
DEFECT DEFINITIONS

OPERATING CONDITIONS

All defect tests performed at T=25oC

SPECIFICATIONS

Classification	Point Defect		Cluster Defect		Maximum Cluster Size	Column Defect	
	Total	Zone A	Total	Zone A		Total	Zone A
C1	≤35	≤14	≤5	≤2	2	0	0
C2	≤90	≤45	≤36	≤18	5	0	0



Point Defects

Dark: A pixel that deviates by more than 6% from neighboring pixels when illuminated to 70% of saturation

-- OR --

Bright: A pixel with a dark current greater than 10,000e/pixel/sec at 25C.

Cluster Defect

A grouping of not more than "Maximum Cluster Size" defects

Column Defect

A grouping of >5 contiguous point defects along a single column

A column containing a pixel with dark current > 30,000e/pixel/sec, OR A column that does not meet the CTE specification for all exposures less than the specified Max sat. signal level and greater than 2 Ke

A pixel which loses more than 250 e under 2Ke illumination

Neighboring Pixels

The surrounding 128 x 128 pixels or ± 64 column/rows

Defect Separation

Column and cluster defects are separated by no less than two (2) pixels in any direction (excluding single pixel defects)

Defect Region Exclusion

Defect region excludes the outer two (2) rows and columns at each side/end of the sensor.